

Search Notes

Application/Control No.

10/629,829

Examiner

Y. Lee

Applicant(s)/Patent under
Reexamination

ISHIZUKA ET AL.

Art Unit

2621

SEARCHED

Class	Subclass	Date	Examiner
375	240.01 240.12 240.28 **	3/14/2007	YL
H04N	7/12		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR